		APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL			Page 1 Appl. No. 286E
Component Title: Capacitors, Microwave, Silicon, MOS, Naked Die based on Types 101M, 201M, 400M and 401M		Executive Member: CNES		Date: 30/04/2019	
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Components (including series and families) submitted for Extension of Qualification Approval:					
ESCC COMPONENT NO.	VARIANTS	RANGE OF COMPONENTS	BASED ON	TEST VEHICLE / S	COMPONENT SIMILAR
5711/002	01 to 31	40V to 200 V	400M	101M104A100M	
				400M106A100M	
				400M108C680M	
Component Manufacturer Cobham Microwave		Location of Manufacturing Plant(s) 31, avenue de la Baltique 91978 Villebon-sur-Yvette Cedex France		Date of original qualification approval: Date: 15/12/2008 Certificate Ref No. 286	
ESCC Specifications used for Maintenance of qualification testing: Generic: 5010 Issue: 3 Detail(s): 5711/002 Issue: 3		Deviations to LVT testing and Detail Specification used: No <input checked="" type="checkbox"/> Yes <input type="checkbox"/> (supply details in Box 15) Deviation from current Specifications: No <input checked="" type="checkbox"/> Yes <input type="checkbox"/> (Supply details)		Qualification Extension Report reference and date: 2017098652-223 dated 25/09/2017 2018019456-223 dated 18/01/2018 20181211476-223 dated 03/01/2019	
8					
Summary of procurement or equivalent test results during current validity period in support of this application (those to ESCC listed first)					
Project Name	Testing Level	LAT	Date code	Quantity Delivered	
Various		Chart F4B	2017 - 2018	>16 000	
PID changes since start of qualification None <input type="checkbox"/> Minor* <input checked="" type="checkbox"/> Major* <input type="checkbox"/> *Provide details in box:		Current PID Verified by: CNES (JLR) Ref No: PID 302 Issue: I Rev Date: 18/04/2019		Name of Executive Representative Date: 18/04/2019	
10					
Current Manufacturing facilities surveyed by: (F. Martin) ESA and CNES (JLR) on 24/09/2014 (Name of Executive Representative) (Date)					
Satisfactory: Yes <input checked="" type="checkbox"/> No <input type="checkbox"/> Explain					
Report Reference: COBH-CIRC-AUD-2014 (ref. ESA-TECQES-RP-0508)					
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Failure Analysis, DPA, NCCS available: Yes ☐ No ☒ (Supply data)

Ref. No's and purposes:

The undersigned hereby certifies on behalf of the ESCC Executive - that the above information is correct; - that the appropriate documentation has been evaluated; - that full compliance to all ESCC requirements is evidence (except as stated in box 15); - that the reports and data are available at the ESCC Executive and therefore applies on behalf of CNES as the responsible Executive Member for ESCC qualification status to be extended to the component(s) listed herein.

Date: 30/04/2019

JP. BUSSENOT

(Signature of the Executive Coordinator)

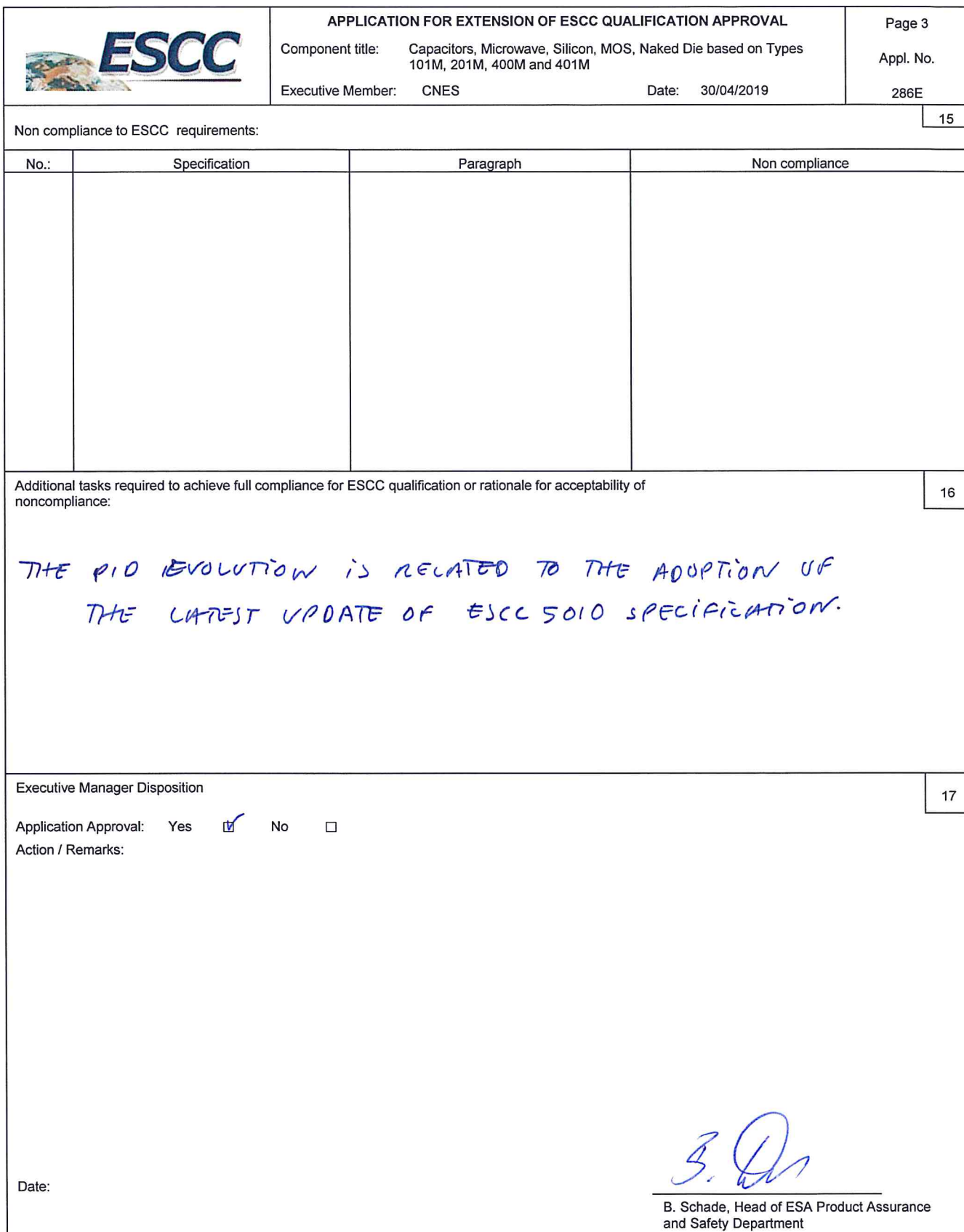
Continuation of Boxes above:

Box 9 :

Editorial changes : new edition of ESCC 5010 (Issue 3) and Detailed Specification ESCC (Issue 4), updated organisation chart.

Box 11 :

The audit performed on Sept. 2014 focussed on the manufacturer's isolator and circulator products. However some areas (back end, screening) and general topics (quality, organisation, ...) are common with the sicilon components manufacturing and have benefited from it.





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ANNEX 1: LIST OF TESTS DONE TO SUPPORT EXTENSION OF QUALIFICATION

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Tests conducted in compliance with:

- ESCC 5010 generic specification; Chart V (for ESCC/QPL parts);
- Or PID-TFD (for ESCC/QML parts)

Tests vehicle identification/description:

101M104A100M	400M106A100M
400M108C680M	

Detail Specification reference: 5711/002

Chart F4B	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if not performed. Comments on Rejection
Environmental/Mechanical Subgroups	Thermal Shock Test	<input type="checkbox"/>	ESCC 5010 Para. 9.5.2				Not required (naked die)
	Shock Test	<input type="checkbox"/>	MIL-STD-750 Test Method 2016				Not required (naked die)
	Vibration Test	<input type="checkbox"/>	MIL-STD-750 Test Method 2056				Not required (naked die)
	Constant Acceleration	<input type="checkbox"/>	MIL-STD-750 Test Method 2006				Not required (naked die)
	Seal Test	<input type="checkbox"/>	MIL-STD-750 Test Method 1071				Not required (naked die)
	Moisture Resistance	<input type="checkbox"/>	MIL-STD-750 Test Method 1021				Not required (naked die)
	Seal Test	<input type="checkbox"/>	MIL-STD-750 Test Method 1071				Not required (naked die)
	Electrical Measurements at Room Temp.	<input type="checkbox"/>	Table 2 of the Detail Specification				Not required (naked die)
	External Visual Inspection	<input type="checkbox"/>	ESCC Basic Specification No. 20500				Not required (naked die)
Endurance Subgroup	Operating Life	<input checked="" type="checkbox"/>	MIL-STD-750 Test Method 1026	1730 1805 1844	8 + 8 + 8	0	
	Electrical Measurements during Endur. Test	<input checked="" type="checkbox"/>	Table 6 of the Detail Specification	1730 1805 1844	8 + 8 + 8	0	
	External Visual Inspection	<input type="checkbox"/>	ESCC Basic Specification No. 20500				Not required (naked die)



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Chart F4B	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if not performed. Comments on Rejection
Electrical Subgroup – Electrical Measurements	Electrical Measurements at Room Temp.	<input type="checkbox"/>	Table 2 of the Detail Specification				Not required (naked die)
	Electrical Measurements at High & Low Temp's	<input type="checkbox"/>	Table 3 of the Detail Specification				Not required (naked die)
	External Visual Inspection	<input type="checkbox"/>	ESCC Basic Specification No. 20500				Not required (naked die)
	Special Testing	<input type="checkbox"/>	The Detail Specification				Not required (naked die)
Electrical Subgroup – Assembly Capability Tests	Solderability Test	<input type="checkbox"/>	MIL-STD-750 Test Method 2026				Not required (naked die)
	Permanence of Marking	<input type="checkbox"/>	ESCC Basic Specification No. 24800				Not required (naked die)
	Terminal Strength	<input type="checkbox"/>	MIL-STD-750 Test Method 2036				Not required (naked die)
De-encapsulation Sub group	Internal Visual Inspection	<input type="checkbox"/>	ESCC Basic Specification No. 20400				Not required (naked die)
	Bond Strength	<input checked="" type="checkbox"/>	MIL-STD-750 Test Method 2037	1730	4	0	
	Die Shear	<input checked="" type="checkbox"/>	MIL-STD-750 Test Method 2017	1730	4	0	

